

# DRAM

# 16 MEG x 1 DRAM

FAST PAGE MODE: MT4C10016  
 STATIC COLUMN: MT4C10017

## FEATURES

- Industry standard x1 pinout, timing, functions and packages
- High performance, CMOS silicon gate process
- Single power supply: +5V±10% or +3.3V±10%
- Low power, 3mW standby; 250mW active, typical
- All inputs, outputs and clocks are fully TTL and CMOS compatible
- Refresh modes:  $\overline{\text{RAS}}$ -ONLY,  $\overline{\text{CAS}}$ -BEFORE- $\overline{\text{RAS}}$  (CBR), and HIDDEN
- 4096-cycle refresh distributed across 64ms

## OPTIONS

- Timing
 

50ns access	-5
60ns access	-6
70ns access	-7
80ns access	-8
- Packages
 

Plastic ZIP (475mil)	Z
Plastic SOJ (400mil)	DJ
Plastic TSOP (*)	TG
- Refresh Period
 

4096 cycles @ 64ms	None
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- Operating Temperature, T<sub>A</sub>

Commercial (0°C to +70°C)	None
Industrial (-40°C to +85°C)	IT
- Power Supply
 

+5V±10%	None
+3.3V±10%	V

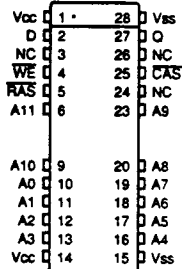
## MARKING

## GENERAL DESCRIPTION

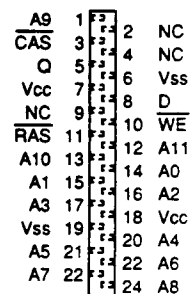
The MT4C10016/7 are randomly accessed solid-state memories containing 16,777,216 bits organized in a x1 configuration. During READ or WRITE cycles, each bit is uniquely addressed through the 24 address bits, which are entered 12 bits (A0-A11) at a time.  $\overline{\text{RAS}}$  is used to latch the first 12 bits and  $\overline{\text{CAS}}$  the latter 12 bits. A READ or WRITE cycle is selected with the  $\overline{\text{WE}}$  input. A logic HIGH on  $\overline{\text{WE}}$  dictates READ mode while a logic LOW on  $\overline{\text{WE}}$  dictates WRITE mode. During a WRITE cycle, data in (D) is latched by the falling edge of  $\overline{\text{WE}}$  or  $\overline{\text{CAS}}$ , whichever occurs last. If  $\overline{\text{WE}}$  goes LOW prior to  $\overline{\text{CAS}}$  going LOW, the output pin

## PIN ASSIGNMENT (Top View)

### 24-Pin SOJ (E-7)



### 24-Pin ZIP



\*Consult factory on availability of TSOP packages

remains open (High-Z) until the next  $\overline{\text{CAS}}$  cycle. If  $\overline{\text{WE}}$  goes LOW after data reaches the output pin, data out (Q) is activated and retains the selected cell data as long as  $\overline{\text{CAS}}$  remains LOW (regardless of  $\overline{\text{WE}}$  or  $\overline{\text{RAS}}$ ). This late  $\overline{\text{WE}}$  pulse results in a READ-WRITE cycle.

FAST PAGE MODE operations allow faster data operations (READ, WRITE or READ-MODIFY-WRITE) within a row address (A0-A11) defined page boundary. The FAST PAGE MODE cycle is always initiated with a row address strobed-in by  $\overline{\text{RAS}}$  followed by a column address strobed-in by  $\overline{\text{CAS}}$ .  $\overline{\text{CAS}}$  may be toggled-in by holding  $\overline{\text{RAS}}$  LOW and strobing-in different column addresses, thus executing faster memory cycles. Returning  $\overline{\text{RAS}}$  HIGH terminates the FAST PAGE MODE operation.

Returning  $\overline{\text{RAS}}$  and  $\overline{\text{CAS}}$  HIGH terminates a memory cycle and decreases chip current to a reduced standby level. Also, the chip is preconditioned for the next cycle during the  $\overline{\text{RAS}}$  high time. Memory cell data is retained in its correct state by maintaining power and executing any  $\overline{\text{RAS}}$  cycle (READ, WRITE,  $\overline{\text{RAS}}$ -ONLY,  $\overline{\text{CAS}}$ -BEFORE- $\overline{\text{RAS}}$  (CBR), or HIDDEN REFRESH) so that all 2048/4096 combinations of  $\overline{\text{RAS}}$  addresses (A0-A10/A11) are executed at least every 32ms/64ms, regardless of sequence. The CBR refresh cycle will invoke the refresh counter for automatic  $\overline{\text{RAS}}$  addressing.

The MT4C10016/7 are available with either 2048 cycles or 4096 cycles of refreshing. If CBR refresh is used, the 2048-cycle version will work in either a 2048 or a 4096 cycle application.

## ORDER INFORMATION

Each Micron component family is manufactured and quality-controlled in the USA at our modern Boise, Idaho, facility employing Micron's low power, high performance CMOS silicon gate process. Micron products are functionally equivalent to other manufacturers' products meeting JEDEC standards. Device functionality is consistently assured over a wider power supply, temperature range and refresh range than specified. Each unit receives continuous

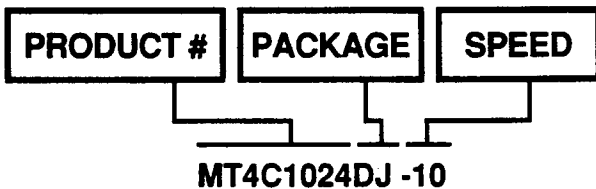
AMBYX™ system-level testing during many hours of accelerated burn-in prior to final test and shipment.

Please contact the factory for technical, test and application assistance. Micron can also furnish the sales representative and distributors nearest you. Micron's quality assured policy is to offer prompt, accurate and courteous service while assuring reliability and quality.

## ORDER EXAMPLES:

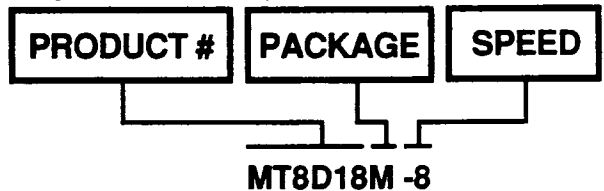
### DRAM

1 Meg x 1, 100ns in Plastic SOJ



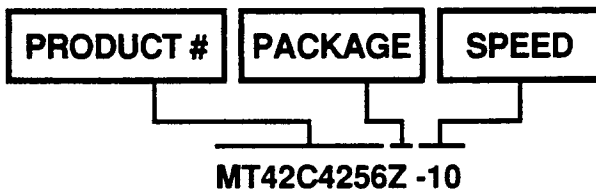
### DRAM MODULE

1 Meg x 8, 120ns Fast Page Mode Access, Leaded SIP



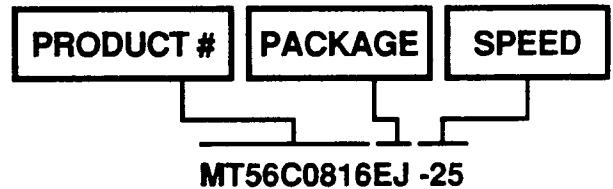
### MULTIPOINT DRAM (VRAM)

256K x 4, 100ns in ZIP



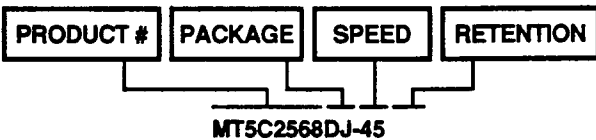
### CACHE DATA SRAM

Dual 4K x 16, Single 8K x 16, 25ns in Plastic LCC



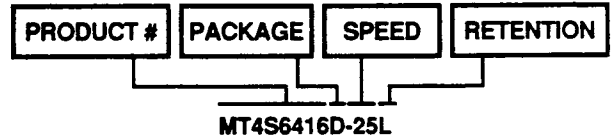
### SRAM

32K x 8, 45ns in Plastic SOJ



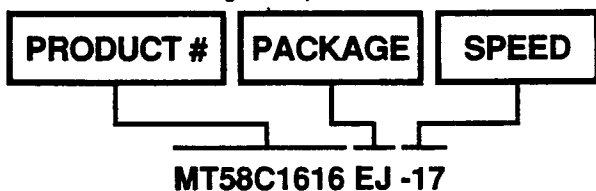
### SRAM MODULE

64K x 16, 25ns in DIP Module with 2V Data Retention



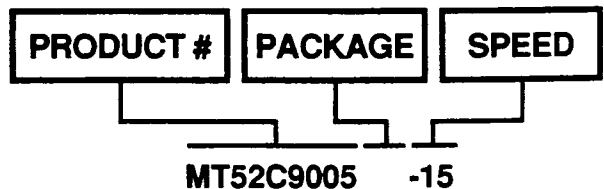
### Synchronous SRAM

16K x 16, Clocked, Register Inputs, 17ns in Plastic LCC



### FIFO

512 x 9, 15ns in 300mil DIP



**NOTE:** Call Micron for to-scale package drawings showing specific dimensions.